IXYS

Advance Technical Information

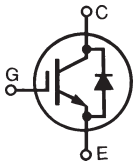
GenX3™ 600V IGBT w/Diode

IXGR72N60A3H1

V_{CES} = 600V
I_{C110} = 52A
$V_{CE(sat)}$ ≤ 1.35V
$t_{fi(typ)}$ = 250ns

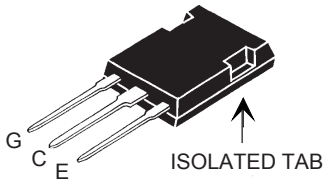
(Electrically Isolated Back Surface)

Ultra-Low Vsat PT IGBT for up to 5kHz Switching



Symbol	Test Conditions	Maximum Ratings	
V_{CES}	T_J = 25°C to 150°C	600	V
V_{CGR}	T_J = 25°C to 150°C, R_{GE} = 1MΩ	600	V
V_{GES}	Continuous	±20	V
V_{GEM}	Transient	±30	V
I_{C25}	T_C = 25°C (Limited by Leads)	75	A
I_{C110}	T_C = 110°C	52	A
I_{F110}	T_C = 110°C	32	A
I_{CM}	T_C = 25°C, 1ms	400	A
SSOA (RBSOA)	V_{GE} = 15V, T_{VJ} = 125°C, R_G = 3Ω Clamped Inductive Load	I_{CM} = 150 V_{CE} ≤ 600	A V
P_C	T_C = 25°C	200	W
T_J		-55 ... +150	°C
T_{JM}		150	°C
T_{stg}		-55 ... +150	°C
V_{ISOL}	50/60 Hz, RMS, t = 1minute I_{ISOL} < 1mA t = 20 seconds	2500 3000	V~ V~
F_C	Mounting Force	20..120/4.5..27	N/lb
T_L	Maximum Lead Temperature for Soldering	300	°C
T_{SOLD}	1.6mm (0.062 in.) from Case for 10s	260	°C
Weight		5	g

ISOPLUS 247™



G = Gate C = Collector
E = Emitter

Features

- Silicon Chip on Direct-Copper Bond (DCB) Substrate
- Isolated Mounting Surface
- 2500V Electrical Isolation
- Optimized for Low Conduction Losses
- Square RBSOA
- Anti-Parallel Ultra Fast Diode
- International Standard Package

Advantages

- High Power Density
- Low Gate Drive Requirement

Applications

- Power Inverters
- UPS
- Motor Drives
- SMPS
- PFC Circuits
- Battery Chargers
- Welding Machines
- Lamp Ballasts
- Inrush Current Protection Circuits

Symbol	Test Conditions (T_J = 25°C, Unless Otherwise Specified)	Characteristic Values Min.	Typ.	Max.	
$V_{GE(th)}$	I_C = 250μA, V_{CE} = V_{GE}	3.0		5.0	V
I_{CES}	V_{CE} = V_{CES}, V_{GE} = 0V			300	μA
	T_J = 125°C			5	mA
I_{GES}	V_{CE} = 0V, V_{GE} = ±20V			±100	nA
$V_{CE(sat)}$	I_C = 60A, V_{GE} = 15V, Note 1			1.35	V

Symbol	Test Conditions (T_J = 25°C, Unless Otherwise Specified)	Characteristic Values Min.	Typ.	Max.	
g_{fs}	I_C = 60A, V_{CE} = 10V, Note 1	48	75		S
C_{ies}	V_{CE} = 25V, V_{GE} = 0V, f = 1MHz		6600		pF
C_{oes}			360		pF
C_{res}			80		pF
Q_g	I_C = 60A, V_{GE} = 15V, V_{CE} = 0.5 • V_{CES}		230		nC
Q_{ge}			40		nC
Q_{gc}			80		nC
$t_{d(on)}$	**Inductive load, T_J = 25°C**		31		ns
t_{ri}	I_C = 50A, V_{GE} = 15V		34		ns
E_{on}	V_{CE} = 480V, R_G = 3Ω		1.4		mJ
$t_{d(off)}$			320		ns
t_{fi}			250		ns
E_{off}			3.5		mJ
$t_{d(on)}$	**Inductive load, T_J = 125°C**		29		ns
t_{ri}	I_C = 50A, V_{GE} = 15V		34		ns
E_{on}	V_{CE} = 480V, R_G = 3Ω		2.6		mJ
$t_{d(off)}$			510		ns
t_{fi}			375		ns
E_{off}			6.5		mJ
R_{thJC}				0.62	°C/W
R_{thCS}			0.15		°C/W

Reverse Diode (FRED)

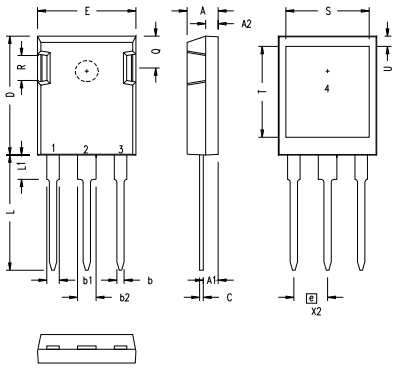
Symbol	Test Conditions (T_J = 25°C, Unless Otherwise Specified)	Characteristic Values Min.	Typ.	Max.	
V_F	I_F = 60A, V_{GE} = 0V, Note 1		1.6	2.0	V
	T_J = 150°C		1.4	1.8	V
I_{RM}	I_F = 60A, V_{GE} = 0V, T_J = 100°C $-di_F/dt$ = 200A/μs, V_R = 300V		8.3		A
t_{rr}	I_F = 60A, -di/dt = 200A/μs, V_R = 300V, T_J = 100°C		140		ns
R_{thJC}				0.8	°C/W

Note 1. Pulse Test, t ≤ 300μs; Duty Cycle, d ≤ 2%.

ADVANCE TECHNICAL INFORMATION

The product presented herein is under development. The Technical Specifications offered are derived from a subjective evaluation of the design, based upon prior knowledge and experience, and constitute a "considered reflection" of the anticipated result. IXYS reserves the right to change limits, test conditions, and dimensions without notice.

ISOPLUS247 (IXGR) Outline



SYM	INCHES MIN	INCHES MAX	MILLIMETERS MIN	MILLIMETERS MAX
A	.190	.205	4.83	5.21
A1	.090	.100	2.29	2.54
A2	.075	.085	1.91	2.16
b	.045	.055	1.14	1.40
b1	.075	.084	1.91	2.13
b2	.115	.123	2.92	3.12
C	.024	.031	0.61	0.80
D	.819	.840	20.80	21.34
E	.620	.635	15.75	16.13
e	.215 BSC		5.45 BSC	
L	.780	.800	19.81	20.32
L1	.150	.170	3.81	4.32
Q	.220	.244	5.59	6.20
R	.170	.190	4.32	4.83
S	.520	.540	13.21	13.72
T	.620	.640	15.75	16.26
U	.065	.080	1.65	2.03

1 – GATE
2 – DRAIN (COLLECTOR)
3 – SOURCE (EMITTER)
4 – NO CONNECTION

NOTE: This drawing will meet all dimensions requirement of JEDEC outline TO-247AD except screw hole.

Fig. 1. Output Characteristics @ 25ºC

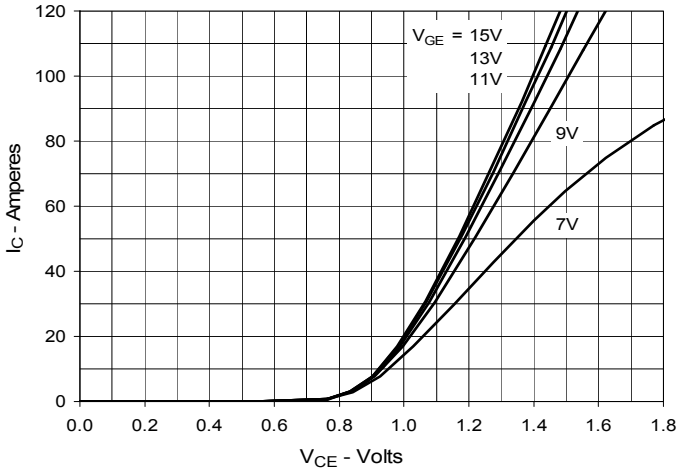


Fig. 2. Extended Output Characteristics @ 25ºC

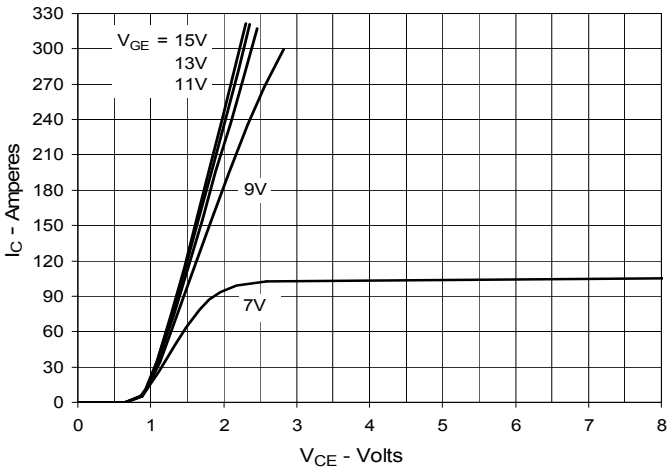


Fig. 3. Output Characteristics @ 125ºC

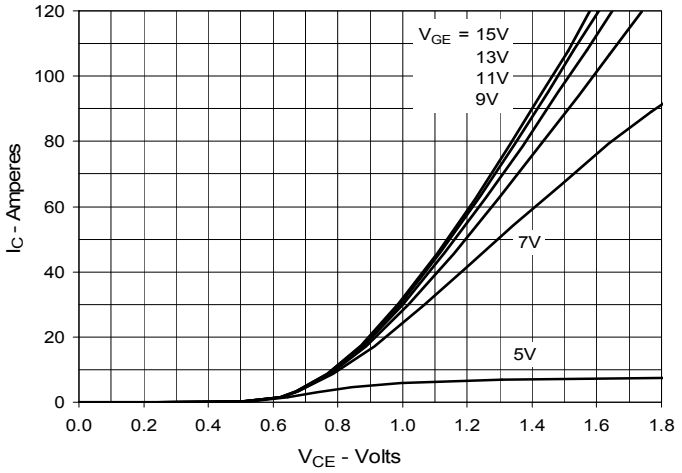


Fig. 4. Dependence of $V_{CE(sat)}$ on Junction Temperature

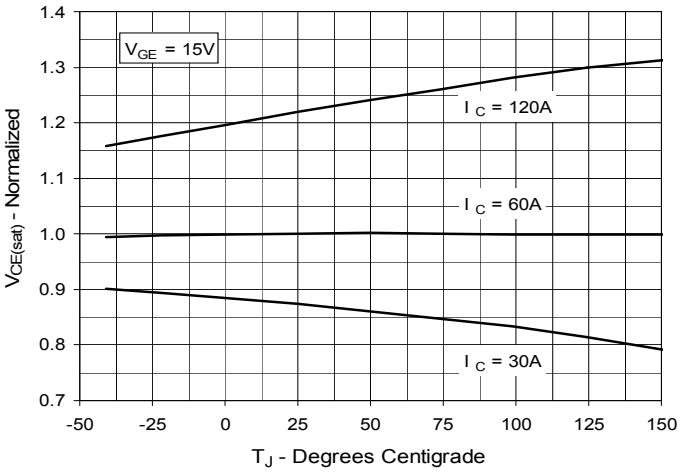


Fig. 5. Collector-to-Emitter Voltage vs. Gate-to-Emitter Voltage

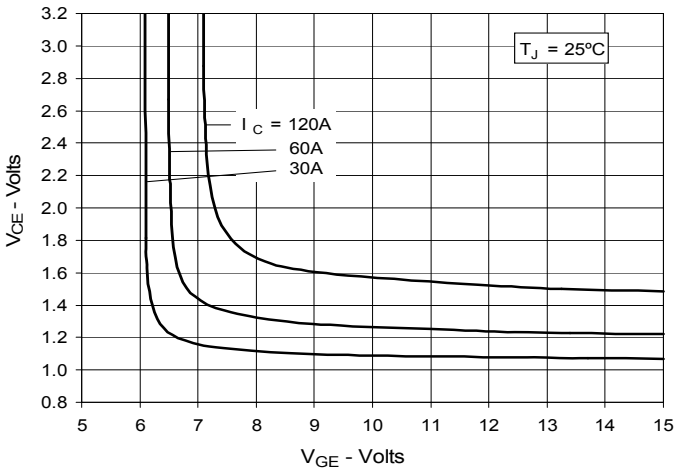


Fig. 6. Input Admittance

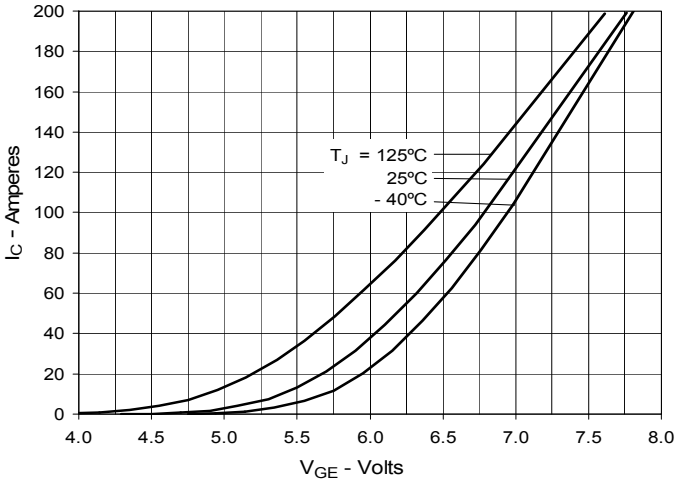


Fig. 7. Transconductance

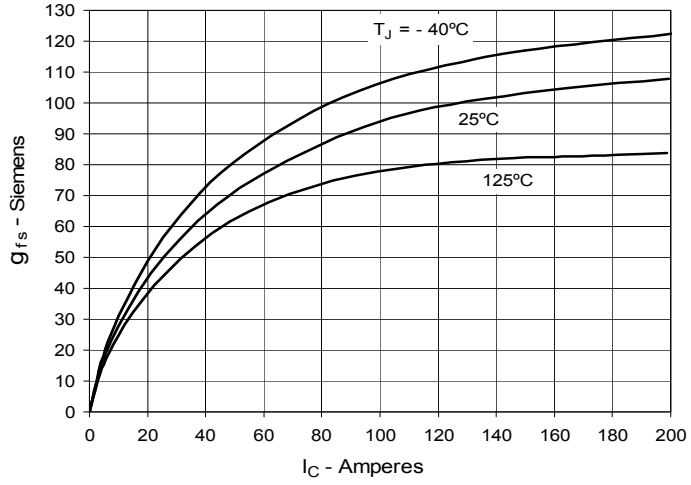


Fig. 8. Gate Charge

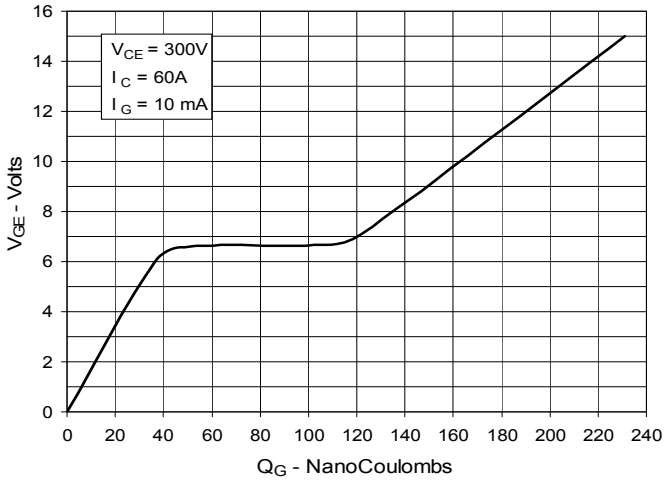


Fig. 9. Capacitance

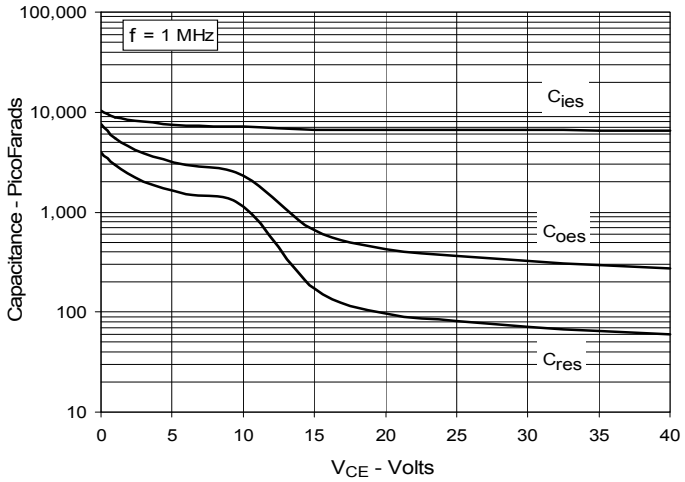


Fig. 10. Reverse-Bias Safe Operating Area

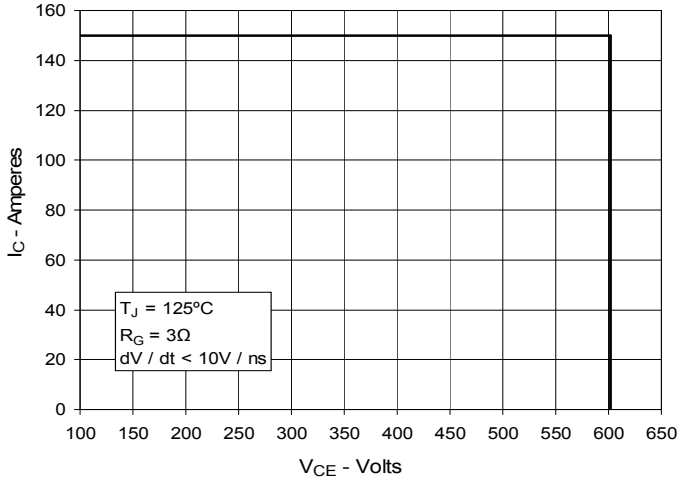
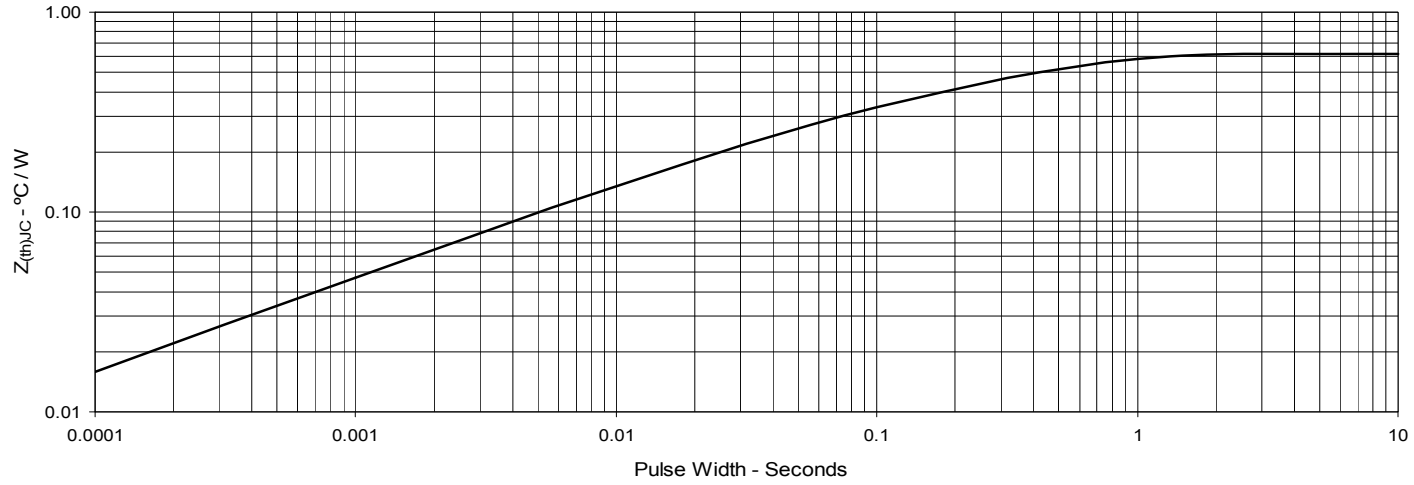


Fig. 11. Maximum Transient Thermal Impedance



IXYS Reserves the Right to Change Limits, Test Conditions, and Dimensions.

Fig. 12. Inductive Switching Energy Loss vs. Gate Resistance

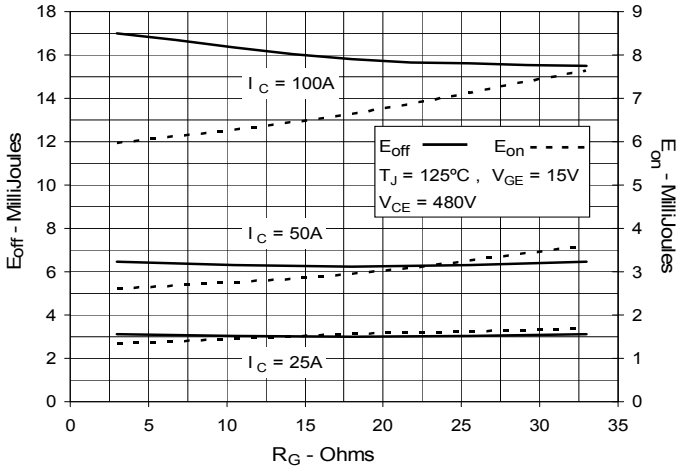


Fig. 13. Inductive Switching Energy Loss vs. Collector Current

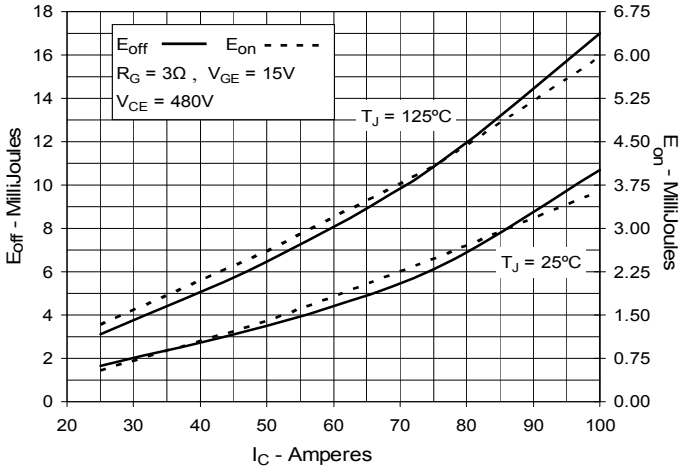


Fig. 14. Inductive Switching Energy Loss vs. Junction Temperature

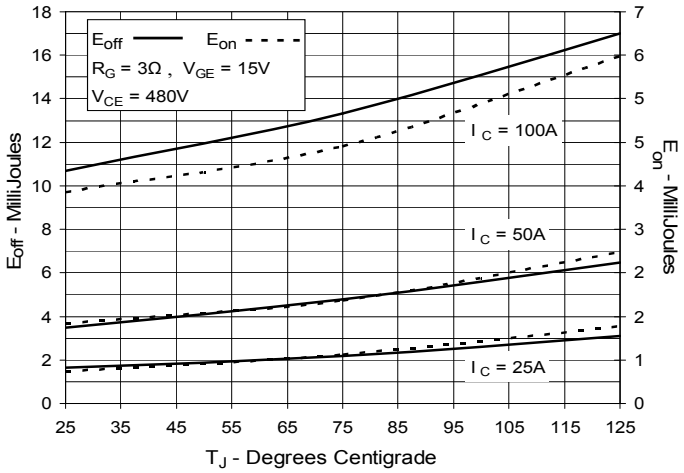


Fig. 15. Inductive Turn-off Switching Times vs. Gate Resistance

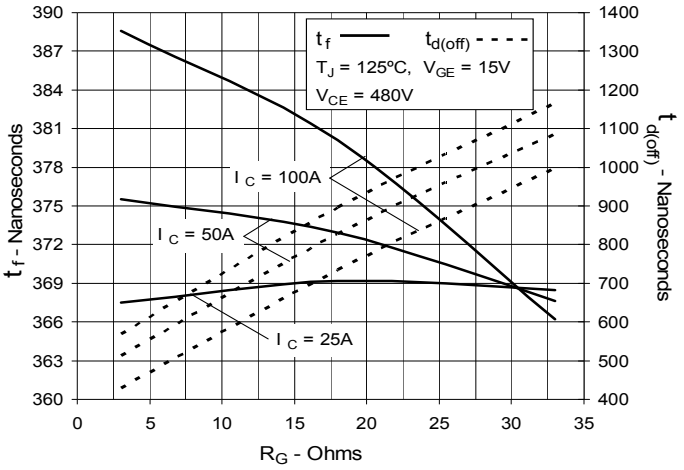


Fig. 16. Inductive Turn-off Switching Times vs. Collector Current

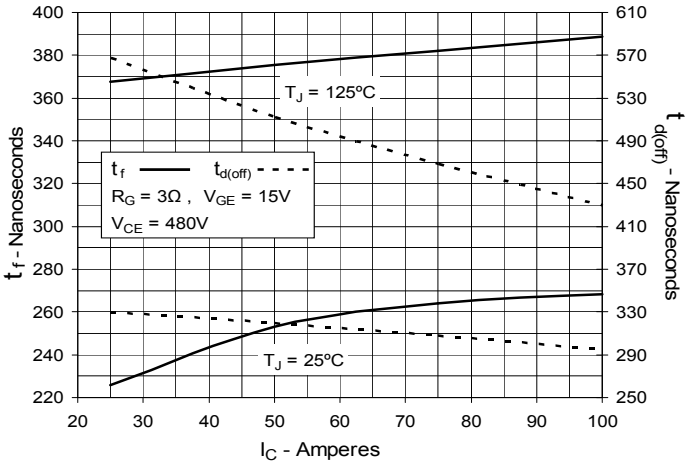


Fig. 17. Inductive Turn-off Switching Times vs. Junction Temperature

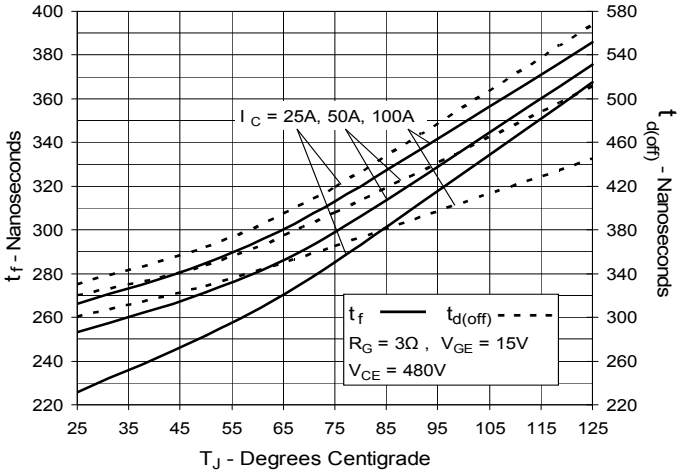


Fig. 18. Inductive Turn-on Switching Times vs. Gate Resistance

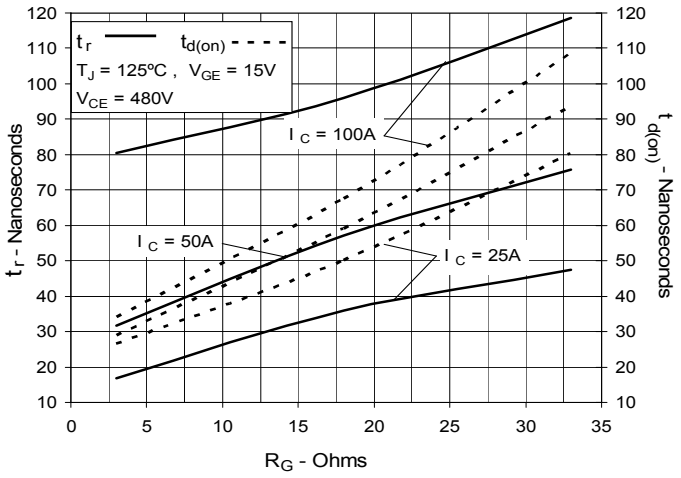


Fig. 19. Inductive Turn-on Switching Times vs. Collector Current

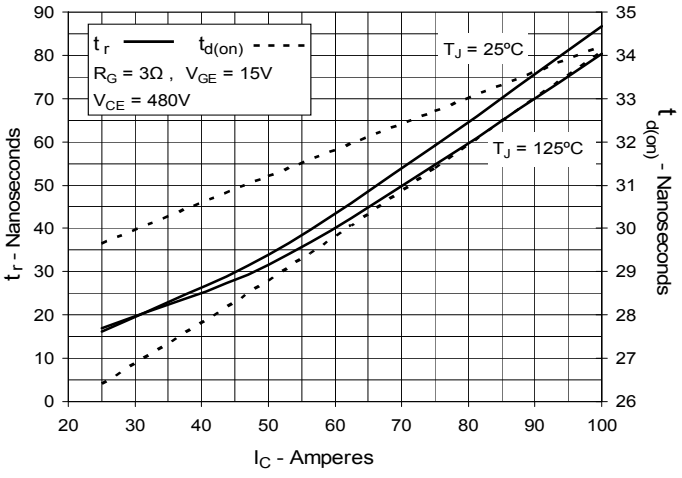
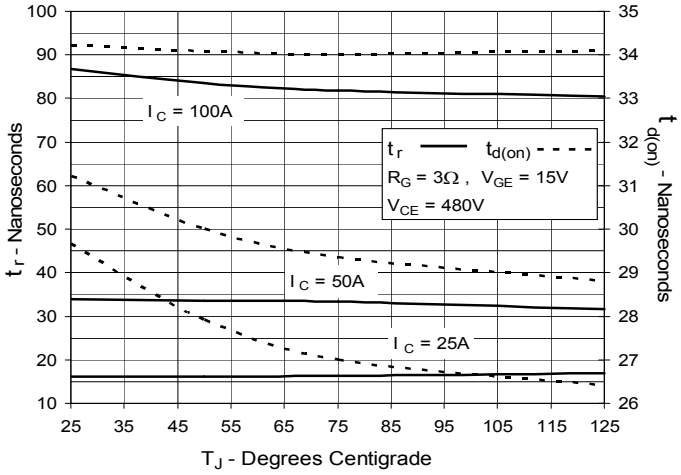


Fig. 20. Inductive Turn-on Switching Times vs. Junction Temperature



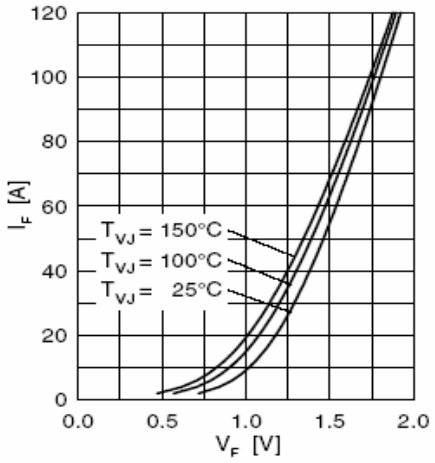


Fig. 21 Forward Current I_F vs. V_F

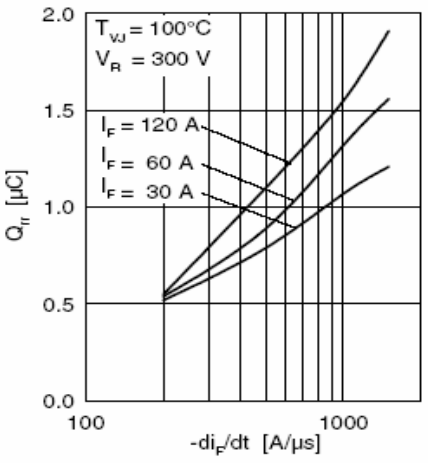


Fig. 22 Typ. Reverse Recovery Charge Q_{rr}

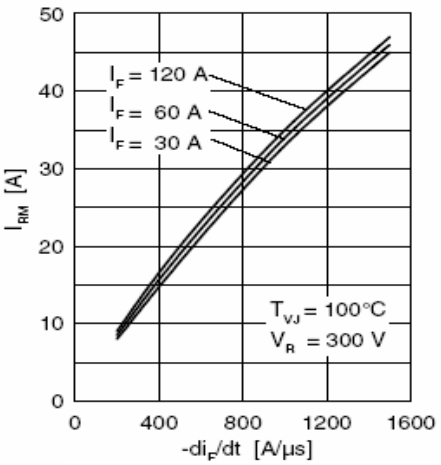


Fig. 23 Typ. Peak Reverse Current I_{RM}

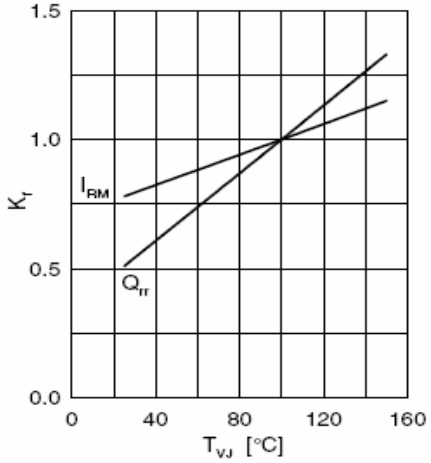


Fig. 24 Typ. Dynamic Parameters Q_{rr}, I_{RM}

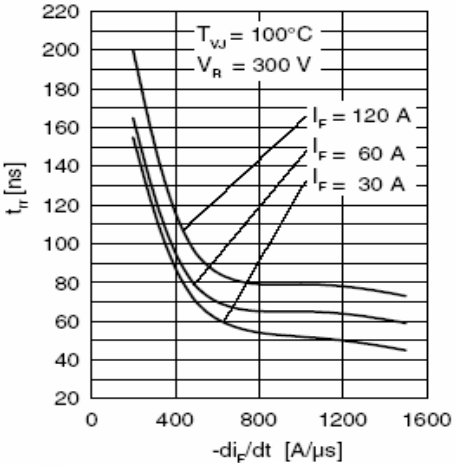


Fig. 25 Typ Recovery Time t_{rr}

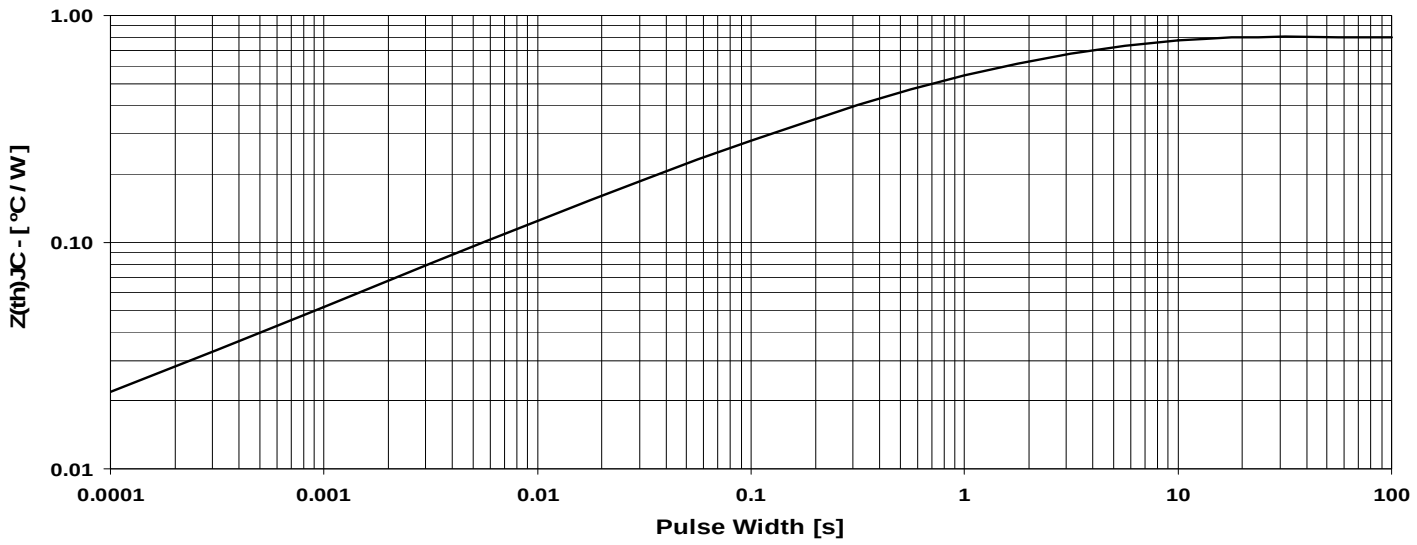


Fig. 26 Maximum Transient Thermal Impedance Junction to Case (for Diode)